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**Bibilashvili et al.**

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(54) **QUANTUM INTERFERENCE DEVICE**(75) Inventors: **Amiran Bibilashvili**, Tbilisi (GE); **Avto Tavkhelidze**, Tbilisi (GE)(73) Assignee: **Borealis Technical Limited** (GI)

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See application file for complete search history.

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(57) **ABSTRACT**

A quantum interference transistor comprising an source region for emitting electron waves into a vacuum, a drain region for collecting the electron waves, a repeating nanostructure in a region between the source and drain regions for introducing a constant phase shift between a plurality of electron waves, and a gate for controlling the phase shift introduced by the nanostructure; wherein the repeating nanostructure is characterized by having sharply defined geometric patterns or indents of a dimension that creates de Broglie wave interference.

18 Claims, 2 Drawing Sheets

